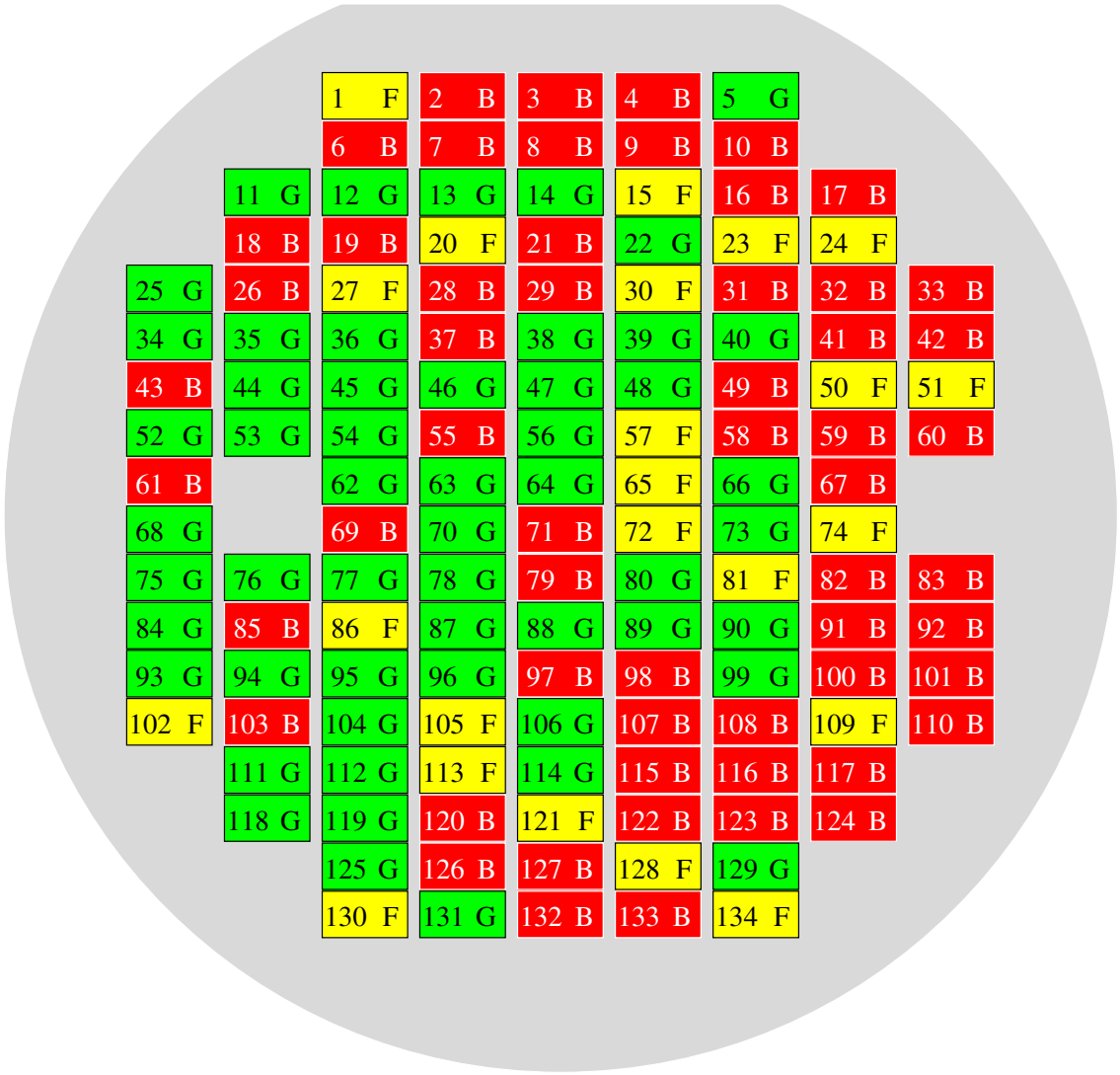
Die quality map for wafer 233 s/n: 21316-16-05

Date: 11/19/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged